

LA-UR-14-23043

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Title: Neutron-Induced failures in Semiconductor Devices

Author(s): Wender, Stephen A.

Intended for: Guest Lecturer

Issued: 2014-04-30



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Neutron-Induced Failures in Semiconductor Devices

Steve Wender

**Los Alamos Neutron Science Center
Los Alamos National Laboratory
Los Alamos, NM**

WPI Seminar

May 7, 2014

Outline

- **Introduction to single event effects**
- **Environmental neutron flux**
- **System response**
- **Los Alamos Neutron Science Center (LANSCE) neutron testing facility**
- **Examples of SEE measurements**
- **Issues for testing, conclusion and summary**

Recent avionics incident highlight Single Event Effects (SEE) problem

- On October 7, 2008, Qantas 72 was enroute from Singapore to Perth, Australia
- “While ..at 37,000 ft, **one of the aircraft’s three Air Data Inertial Reference Units (ADIRU) started outputting intermittent, incorrect values...** Two minutes later ...the aircraft flight control primary computers **commanded the aircraft to pitch down. ... At least 110 of the 303 passengers and nine of the 12 crew members were injured:** 12 of the occupants were seriously injured and another 39 received hospital medical treatment.” (Pg. vii)
- “The other potential **triggering event was a single event effect (SEE)** resulting from a high-energy atmospheric particle striking one of the integrated circuits within the CPU module. There was insufficient evidence available to determine if an SEE was involved, but **the investigation identified SEE as an ongoing risk for airborne equipment.**” (pg. xvii)
- “Testing was conducted with neutrons at 14 MeV ...the test was not sufficient to examine the susceptibility to the full range of neutrons at the higher energy levels that exist in the atmosphere”. (pg. 147)

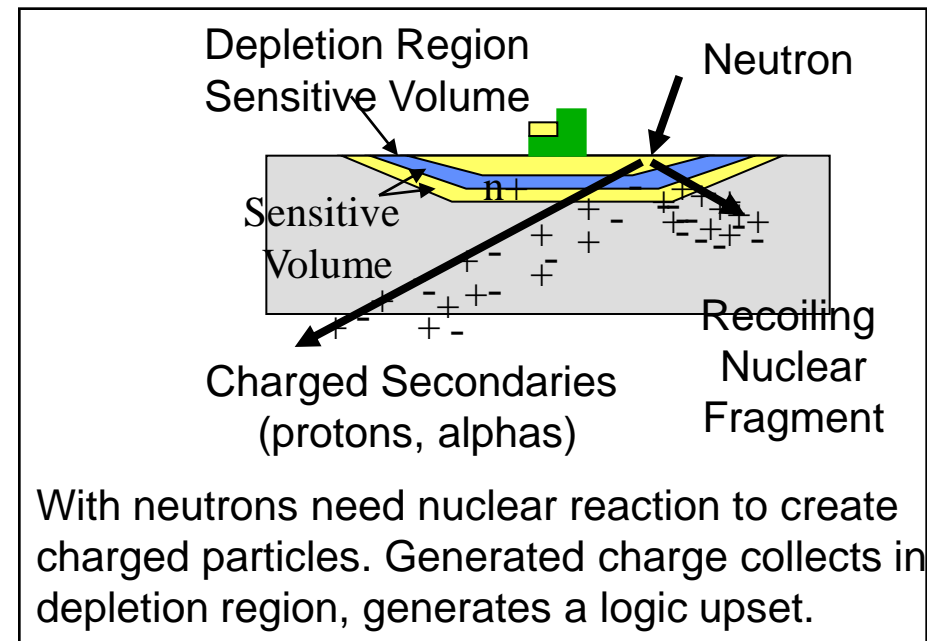
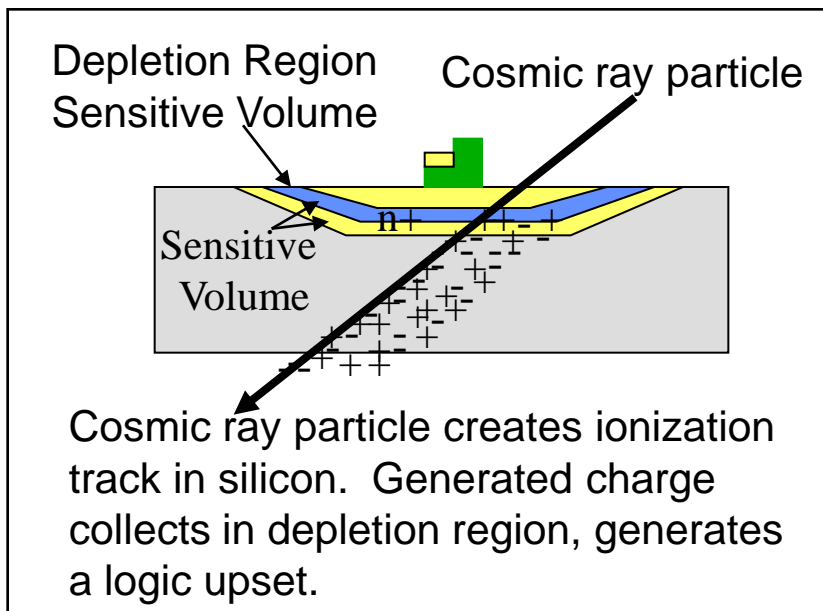
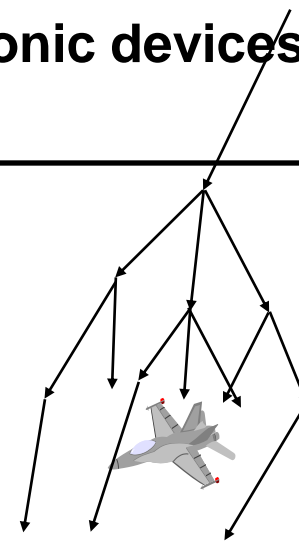
ATSB Transport Safety Report Aviation Occurrence
Investigation AO-2008-70



- “The ATSB received expert advice that **the best way of determining if SEE could have produced the data-spike failure mode was to test the affected units at a test facility that could produce a broad spectrum of neutron energies.** However, the ADIRU manufacturer and aircraft manufacturer did not consider that such testing would be worthwhile for several reasons, including that:
- There were significant logistical difficulties in obtaining access to appropriate test facilities”

Neutron Single Event Effects (SEE) are faults in electronic devices caused by neutrons from cosmic rays

- Neutrons are produced by cosmic rays in the upper atmosphere
- Neutrons have long mean-free paths so they penetrate to low altitudes
- Neutrons interact with Si and other elements in the device to produce charged particles
- Charged particles deposit charge in sensitive volume which cause state of node to change



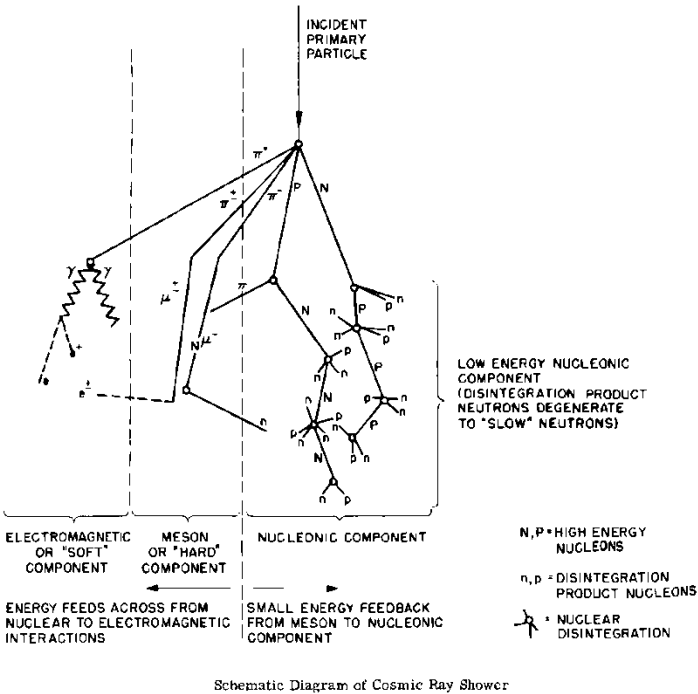
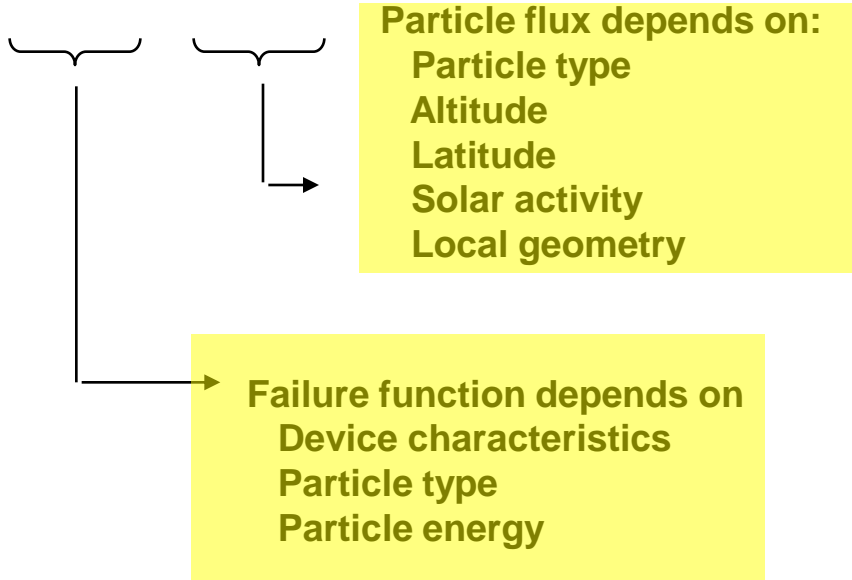
Many types of single-event effects can cause failures

- **Soft errors**
 - Single event upset
 - Multiple event upset (a few % of SEU rate)
 - Silent data corruption
- **Hard errors**
 - Single event latchup
 - Single event burnup, gate rupture, etc.
- **High power devices**
- **First experiments were performed by the Boeing Co. for 777 certification**
- **Industry trends to lower voltages and smaller feature size are thought to increase the failure rate due to SEE**
- **Similar devices have very different failure rates**
- **The failure rate due to SEU is equal to all the other failure modes combined**
- **“ Since chip SER is viewed by many as a legal liability (something that you know may fail) the public literature in this field is sparse and always makes management nervous”. *SER History, Trends and Challenges*
James Ziegler and Helmut Puchner**

Cosmic-ray induced failure rates

- The failure rate due to cosmic-ray events is given by:

$$F/t = \sum_p \int f_p(E_p) * \Phi_p(E_p) \, dE_p$$



F/t is the number of fails / time

p is the particle type (neutron, protons, pions,...)

f_p(E_p) is the number of fails /particle with energy E_p

Φ_p(E_p) is the number of particles/sec with energy E_p

The cosmic-ray neutron flux depends on altitude

- Neutron flux at different altitudes can be obtained by

$$I(A_1)/I(A_2) = \exp[(A_2 - A_1)/L]$$

L is attenuation length of particle

L ~ 136 cm²/g for neutrons

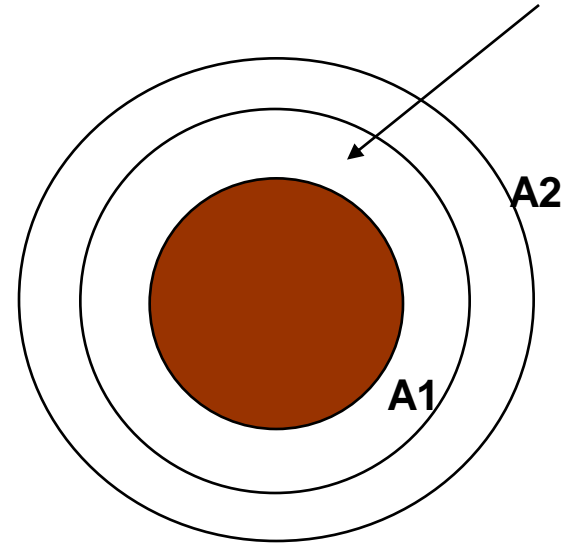
L is different for other particles

A is the thickness of the air in g/cm²

$$A(H) = 1033 - (0.3648H) + 4.2610^{-7}H^2 \text{ grams/cm}^2$$

H is the altitude above sea level in ft

(Zeigler, IBM Journal of Research and Dev. 42, 1998)



Thickness of air at sea level is 1033 g/cm² which is equivalent to over 4 feet of steel or 10 feet of concrete !!!

Energy dependence of cosmic-ray neutron flux

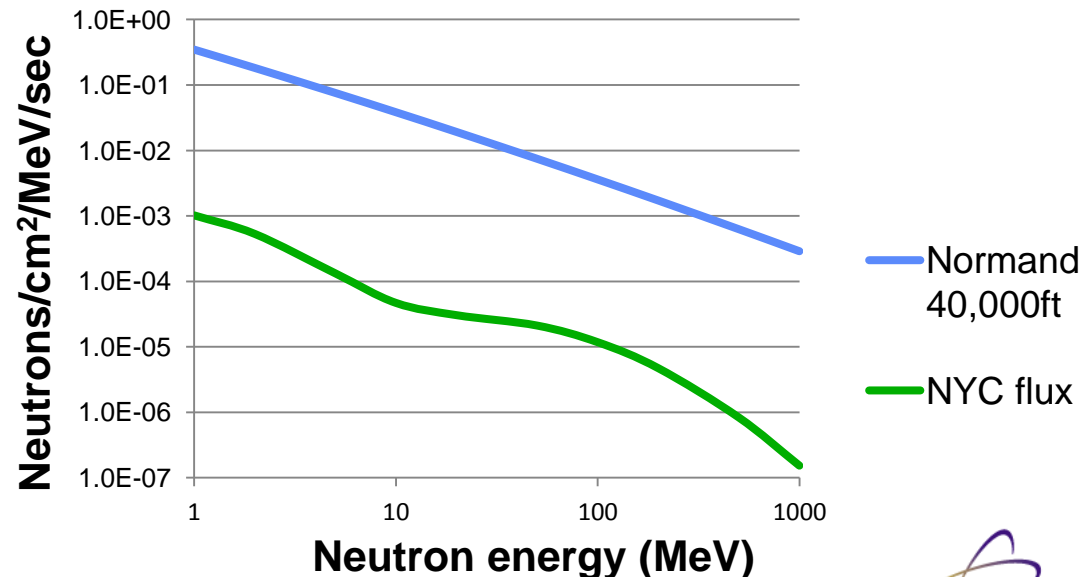
- Neutron flux at 40,000 ft and 45° latitude (Normand, IEEE Trans. Nucl. Sci. 43, 1996, 461)

$$\Phi_n(E_n) = 0.3459 \cdot E_n^{-0.9219} \cdot \exp[-0.01522(\ln(E_n))^2] \quad \text{n/cm}^2/\text{sec/MeV}$$

- Neutron flux at NYC

$$\Phi_n(E_n) = 1.006 \times 10^{-6} \cdot \exp(.35 \cdot (\ln(E_n))^2 + 2.1451 \cdot \ln(E_n)) \\ + 0.001011 \cdot \exp(-0.4106 \cdot (\ln(E_n))^2 - 0.667 \cdot \ln(E_n)) \quad \text{n/cm}^2/\text{sec/MeV}$$

E_n is neutron
energy in MeV



Cosmic-ray neutron flux depends on latitude

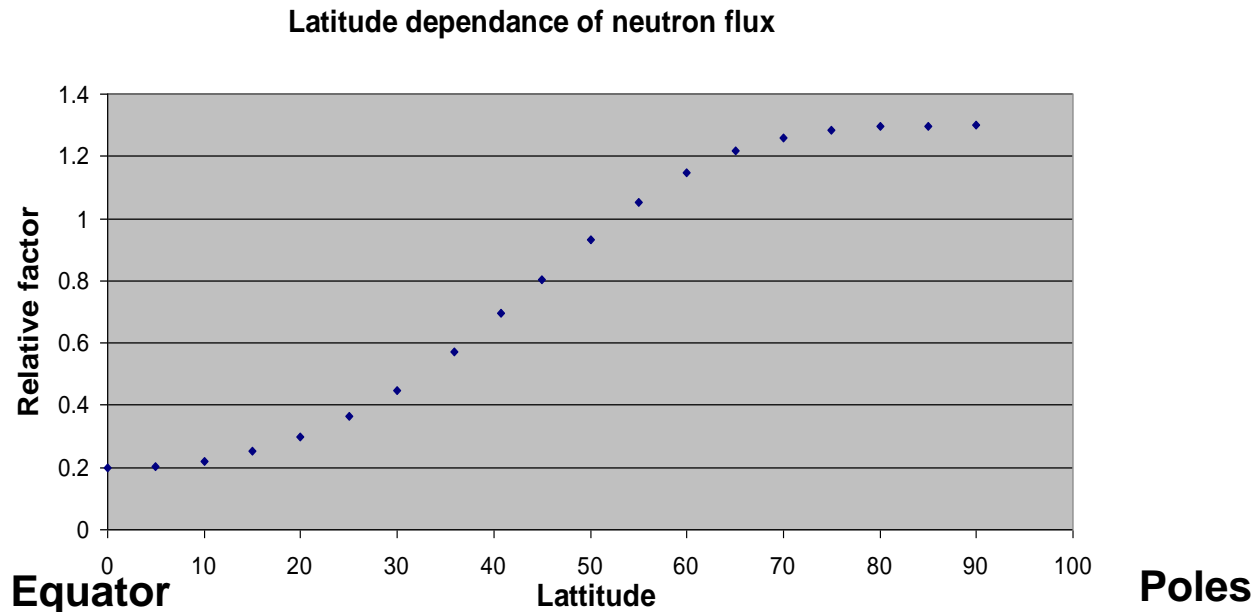
- The cosmic ray neutron flux depends on the latitude and is parameterized by the following expressions:

$$F(L)=0.6252*\exp[-0.461\cos^2(2L)-0.94\cos(2L)+0.252]$$

(Normand, IEEE Trans. Nucl. Sci 43, 1996, 461)

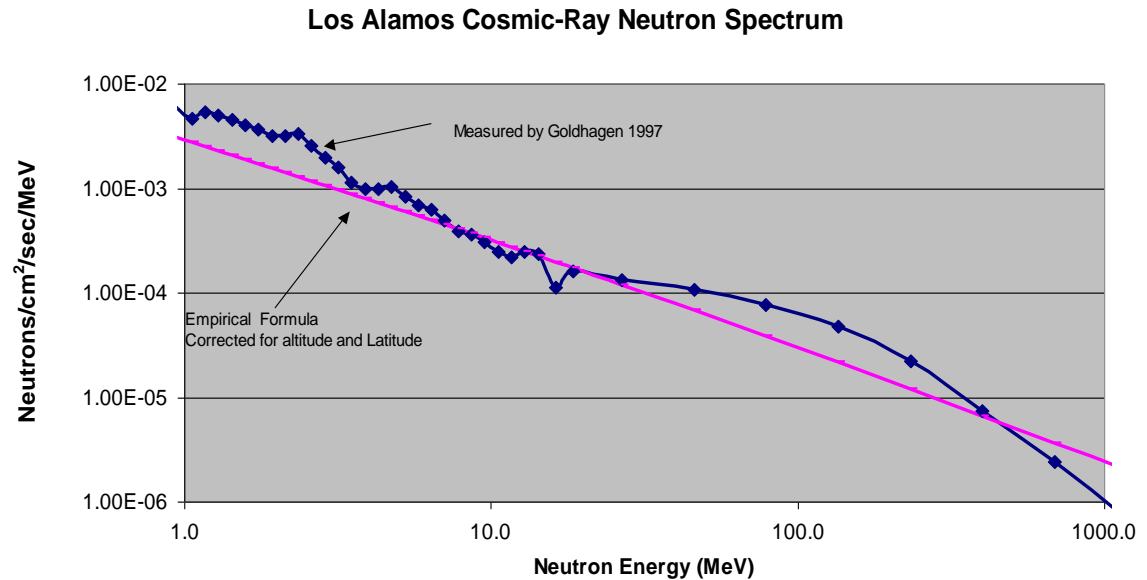
L is the latitude in degrees

- Shape changes with latitude



Measured cosmic ray flux agrees with formulas at 7000 ft at Los Alamos

- The neutron flux was measured by Goldhagen et al. (1997) using Bonner spheres



Integrated cosmic-ray neutron flux above 10 MeV (neutrons/cm²/sec)

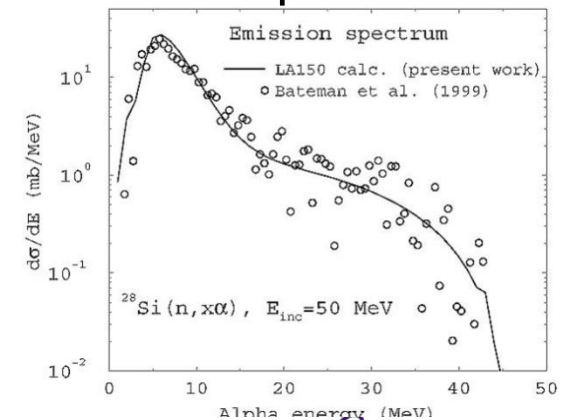
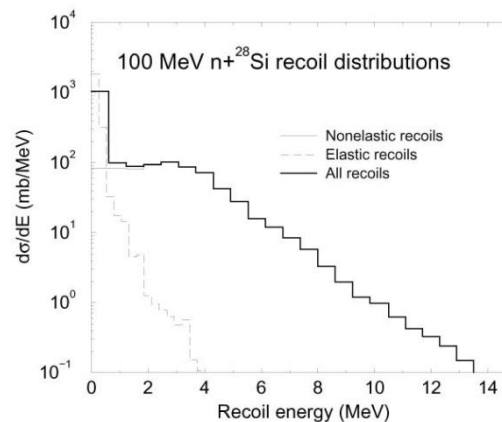
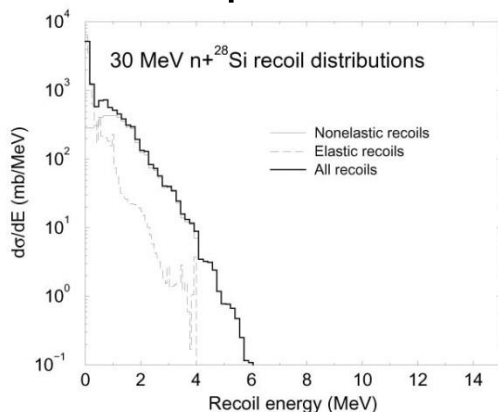
	n/cm2/s	Relative
Sea level (New York City)	0.00565	1
7000 ft (Los Alamos)	0.019	3.4
40,000 feet	1.53	270

When neutrons interact with Si many charged particles are produced

- Neutrons strike silicon and produce recoil Silicon nuclei and alpha particles, etc.

Incident neutron energy (MeV)	Max recoil energy (MeV)	Range of particle in Si (μm)	Energy loss (keV/ μm)
30	6 (Si)	3.6	2750
100	14 (Si)	6.2	3300
50	40 (α)	710	32

- Simple models exist to estimate upset rates based on recoil spectra



Accelerated testing is essential

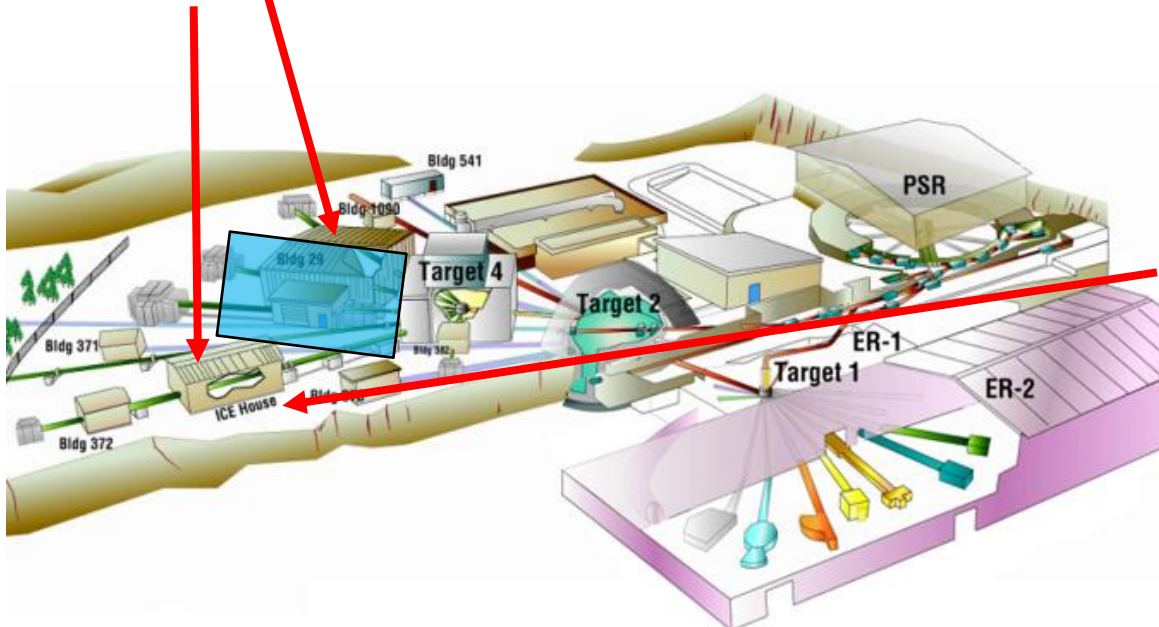
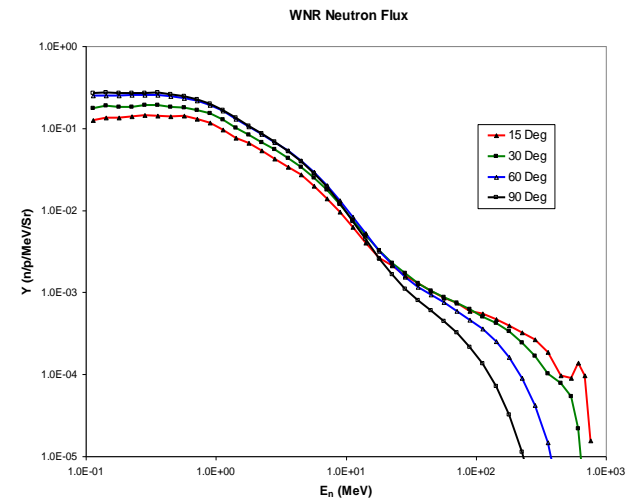
- **Design criteria for servers (100 GB memory) is 1 fail / year from SEU**
 - If need to know the failure rate to 10%, need 100 fails
 - Need to run server for 100 years! RAMs change every 18 months
- **Need to perform accelerated testing with acceleration rate~ 5000 (3.6×10^4) to get answer in 1 week (1 day) if testing entire server**
- **Need to test individual chips before they go into system**
 - A 100GB server may have ~300 memory chips
 - The failure rate of a single chip is 1 fail / 300 years
- **This requires an acceleration factor of $\sim 10^7$ for 1 day of testing to get 100 fails**

Los Alamos Neutron Science Center (LANSCE)



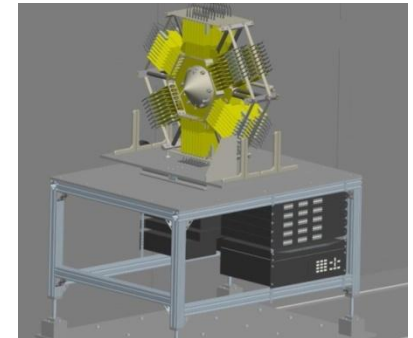
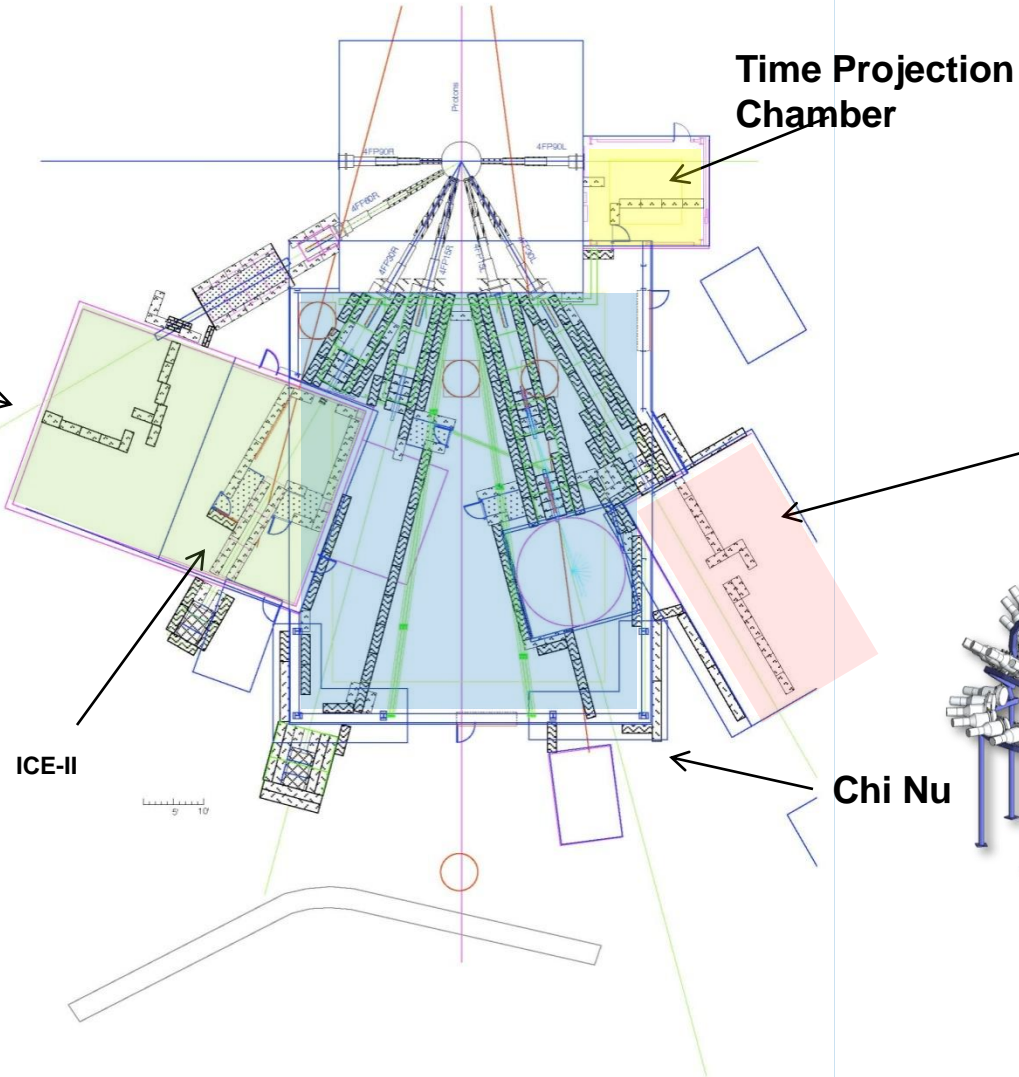
The high-energy neutron spallation source at LANSCE

- **5 μA (1 KW in target) of proton current for high-energy neutron production (Target-4)**
 - Neutrons are produced via spallation reactions with tungsten target
 - Tungsten target is 7.5 cm long and 3 cm diam no moderation
 - Target is located inside a 2 m diam vacuum chamber
 - Massive shielding around target
 - Six flight paths operate simultaneously
- **Neutron Single Event Effect flight path and test area. Second area developed in 2012**

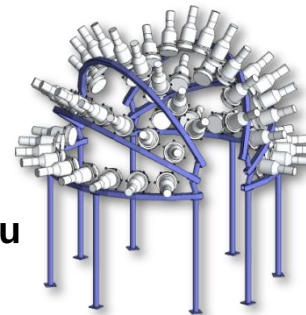


High-energy neutron flight paths at LANSCE/WNR

GEANIE



ICE House



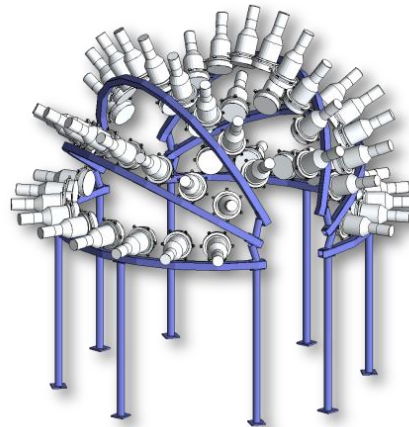
Chi Nu

Many instruments have been developed for nuclear science measurements at LANSCE

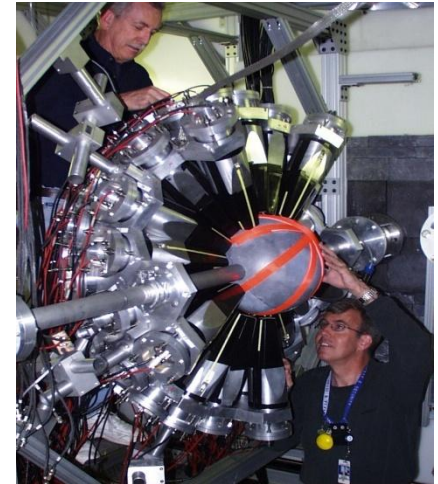
GEANIE ($n, x\gamma$)



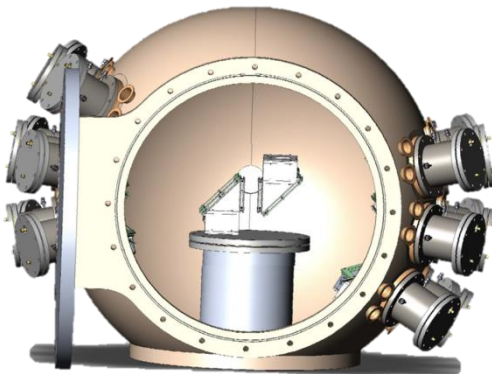
Chi Nu ($n, xn+\gamma$)



DANCE (n, γ)



SPIDER

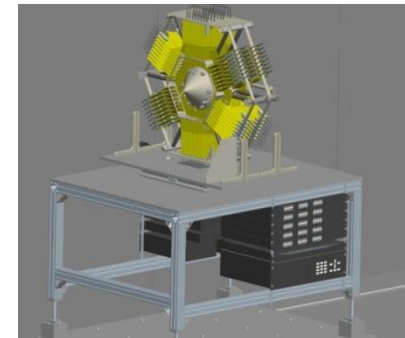


Fission

LSDS

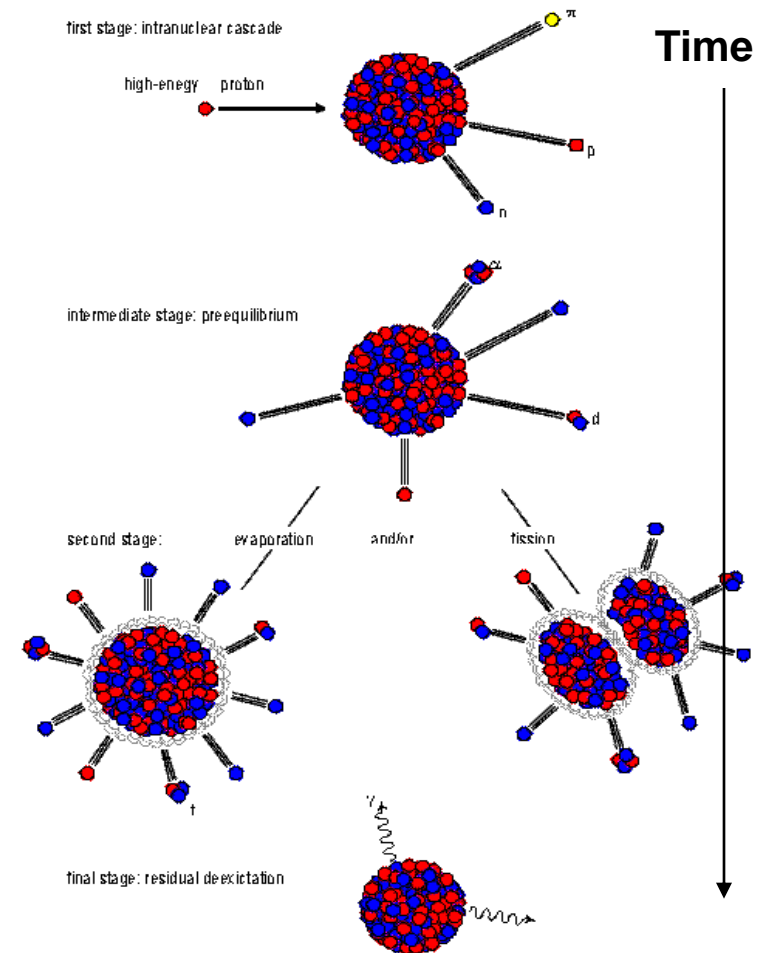


TPC



Neutrons at LANSCE are produced by spallation reactions

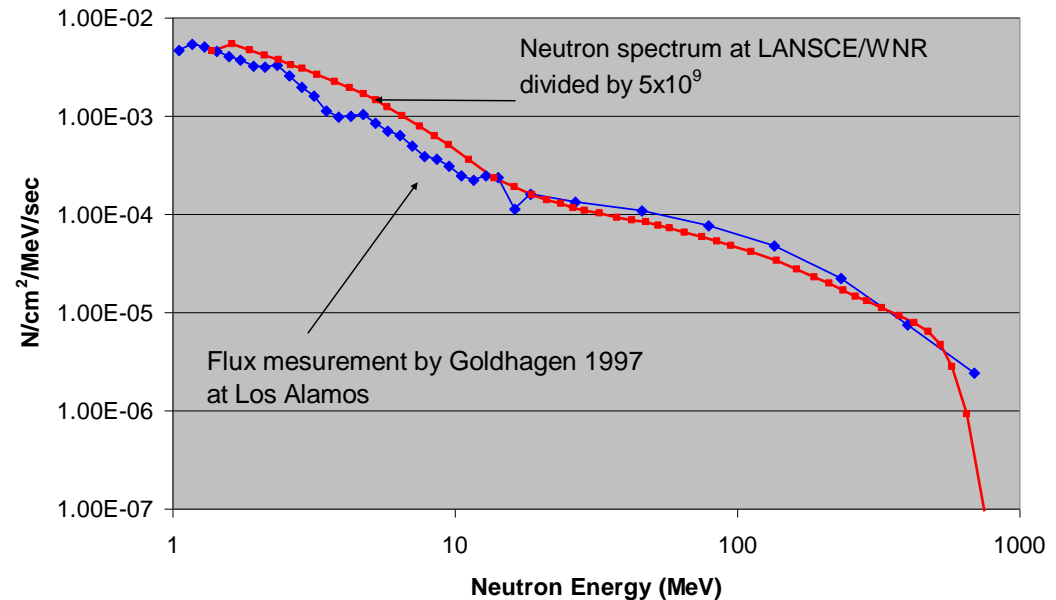
- Difficult to produce high-energy neutrons. No charge- can't accelerate
- Spallation reactions occur when high energy particles strike a high z target. Spallation reactions produce a wide range of output particles
- In the first stage of the reactions, high-energy nucleons are produced
- At later times, the nucleus "thermalizes" and lower energy neutrons and nuclei are produced
- Charged particles are removed from the neutron beam by magnets



The high-energy spallation neutron sources provide excellent capability for SEE testing and measuring

- Because neutrons are produced by spallation by the same basic process as in the atmosphere, the neutron spectrum can be similar to the neutron spectrum produced by cosmic rays in the atmosphere
- Neutron spectrum determined precisely by time-of-flight techniques

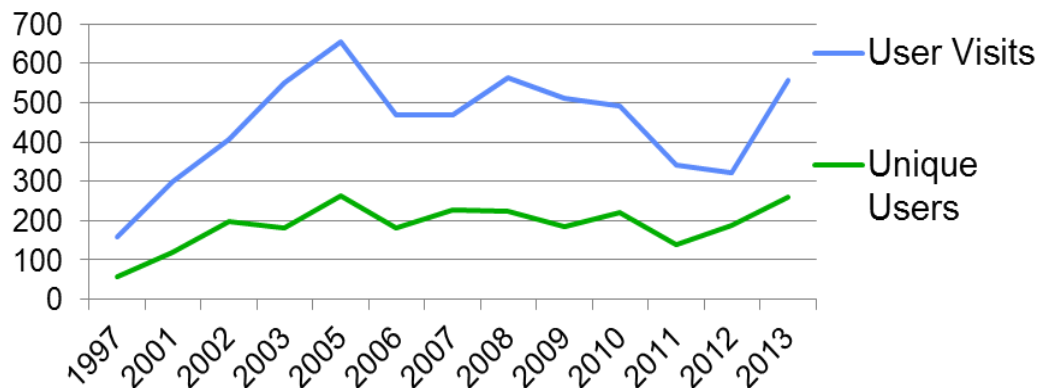
Neutron Flux at Los Alamos and LANSCE/WNR



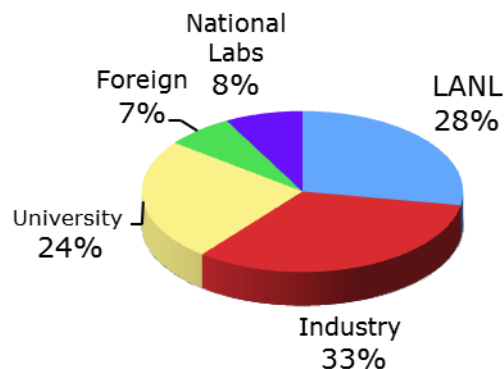
- Accelerated soft error rate (SER) testing is the preferred method to determine failure rates (JESD89)
 - LANSCE beam intensity is approximately 10^6 - 10^8 times greater than the flux at aircraft altitudes or sea level. One hour of testing is equivalent to over 100 years of testing at aircraft altitudes.
 - Direct and accelerated SER measurement are more reliable than projections from mono-energetic sources
 - Devices may be placed in the beam in air and operated under normal conditions.

Nuclear Science User Program statistics for 2013 run cycle

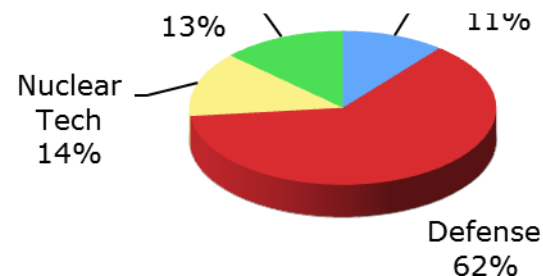
Nuclear Science Users



Unique Users 2012



Nuclear Science Proposals



Several neutron sources provide testing capabilities

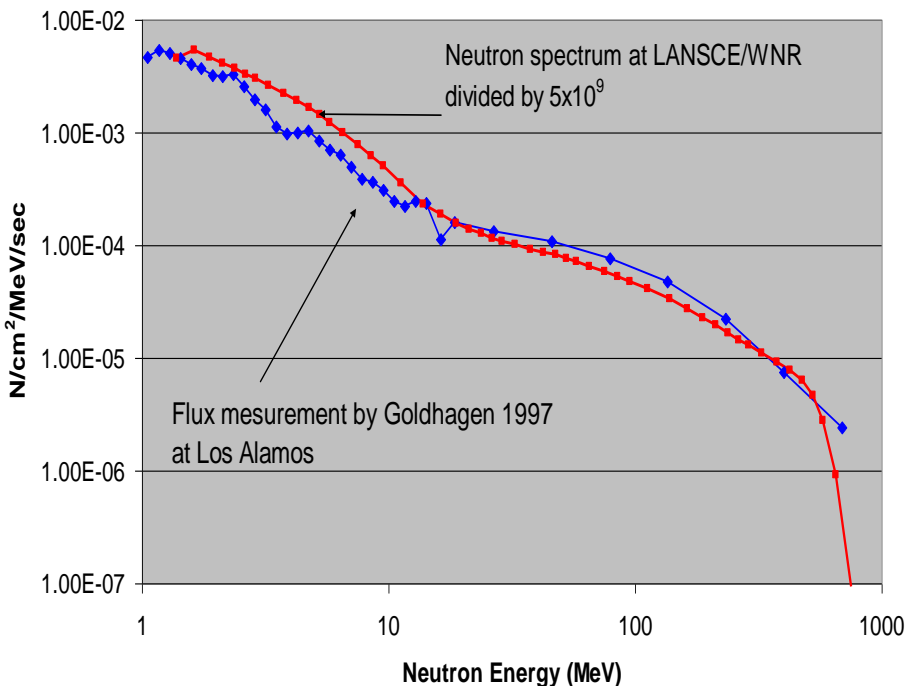
Facility	LANSCCE	TRIUMF	TRIUMF	TSL
Location	USA	Canada	Canada	Sweden
Beam energy	800	400	116	180
Neutrons/cm ² /s	5x10 ⁵ / 1.2x10 ⁶	3x10 ⁶	5x10 ⁴	10 ⁶
Spot size (cm)	2.5,5,8	5X12	20X100	1-30
Operation (hrs/year)	3000*2	3000	800	9 mo

Notes:

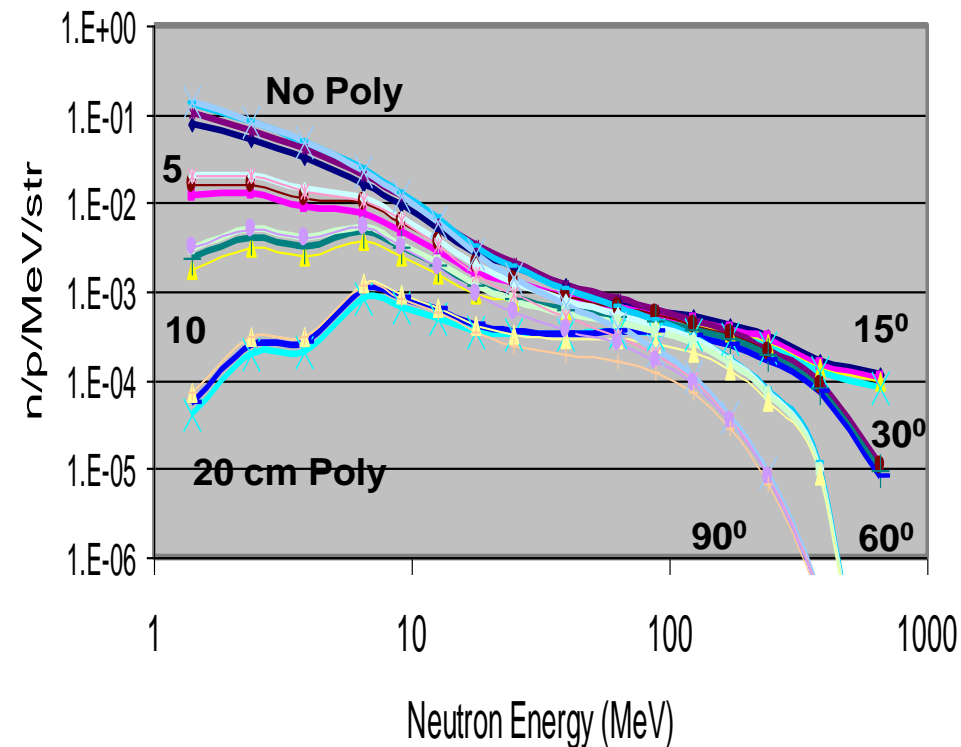
1. Research Center Nuclear Physics at Osaka Japan also does semiconductor testing
2. TSL facility is uncertain beyond 2015
3. CHIPIR facility at ISIS (~10⁶ n/cm²/s) begin operation 3/2014
4. Two flight path at LANSCCE for testing . New flight path has twice flux as old Flight Path
5. LANSCCE neutron intensity will increase X2.5 in 2014

The LANSCE neutron spectrum is similar to the atmospheric neutron spectrum produced by cosmic rays

Neutron Flux at Los Alamos and LANSCE/WNR

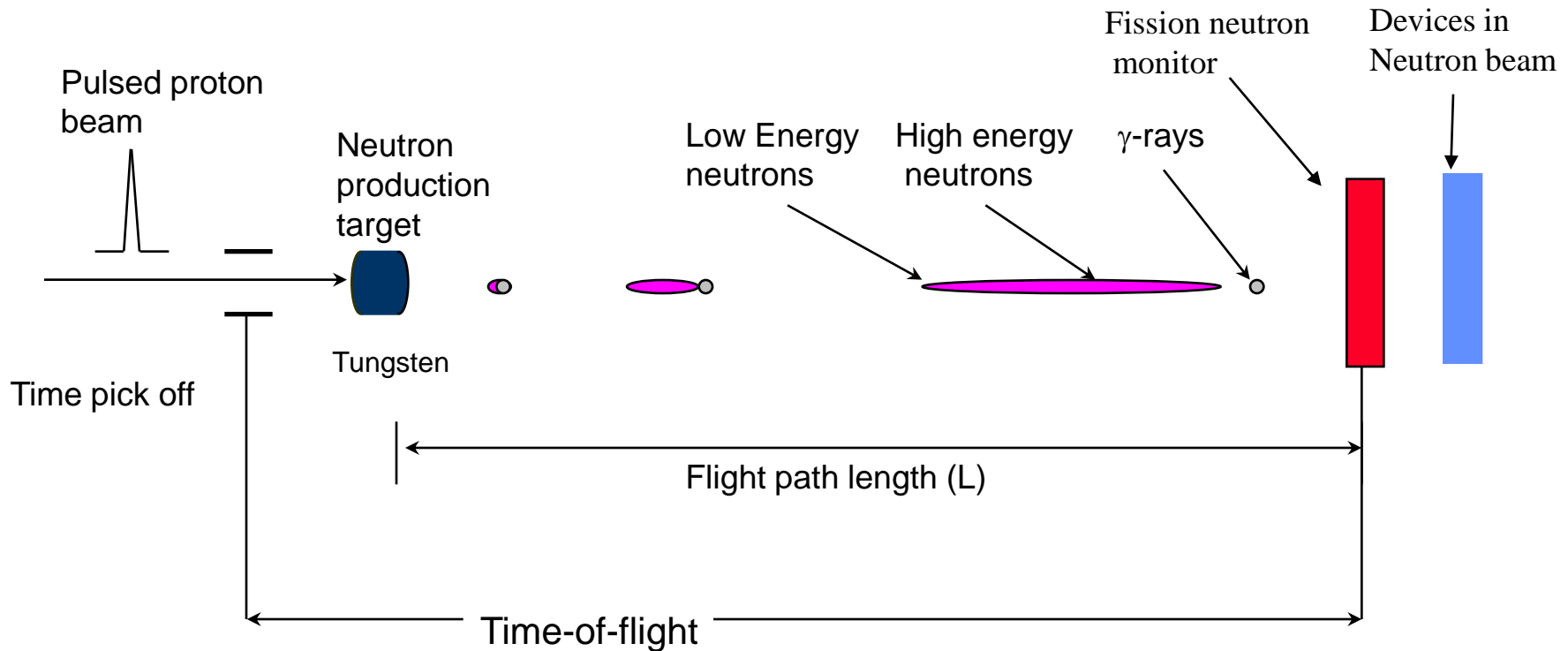


Neutron spectra for various flight paths and absorbers



- The 30-degree flight path with no absorbers provides the best match for the cosmic-ray neutron spectrum

Neutron energies are determined by Time-of-Flight



$$\text{Neutron TOF} = \frac{72.3 L}{\sqrt{E_n}} \quad (\text{non-relativistic})$$

$$\gamma\text{-ray TOF} = \frac{L}{c} \quad c \text{ is velocity of light}$$

Example: $L = 20\text{m}$

$E_n = 1 \text{ MeV}$	$E_n = 100 \text{ MeV}$
$\text{TOF}_n = 1.5 \mu\text{s}$	$\text{TOF}_n = 150 \text{ ns}$
$\text{TOF}_\gamma = 67 \text{ ns}$	

LANSCCE proton beam parameters

- **Time structure**

- Macropulses

- » ~625ms wide

- » 100 macropulses/s **presently 40 MP / sec**

- μ pulses

- » Within each macropulse are μ pulses. μ pulses are separated by integral multiples of 180 ns. Typically μ pulse separation is 1.8 μ s

- » Width of μ pulse is < 1 ns

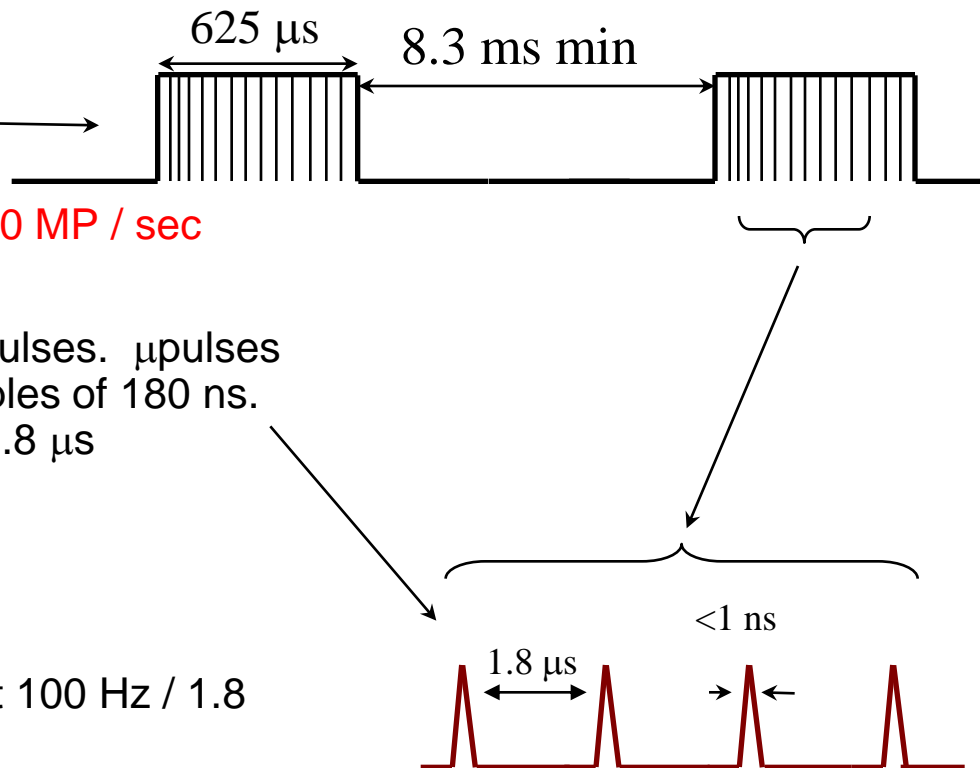
- **Intensity**

- Approximately 5×10^8 protons/ μ pulse

- Approximately 35,000 μ pulses/s (at 100 Hz / 1.8 μ sec spacing)

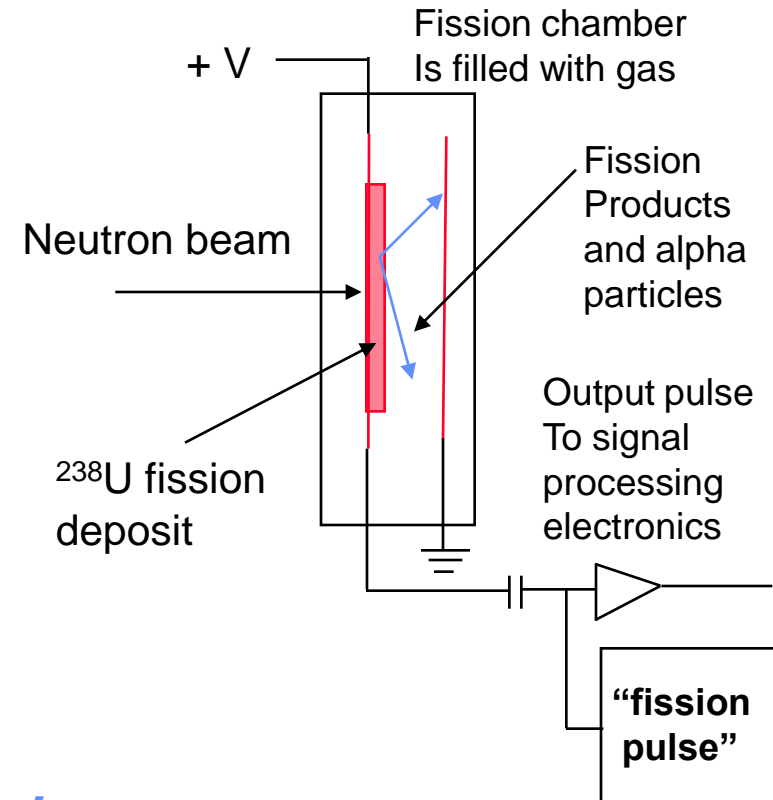
- Average proton beam current is 5 μ A (at 100 Hz)

- Approximately 30 neutrons($E_n > 1$ MeV) / μ p/cm²



Neutron flux is monitored using a fission ionization chamber

- Neutron monitor measures the shape and magnitude of the neutron spectrum
- Neutron monitor is “thin” so it does not perturb the beam
- Neutron monitor provides a signal to the experimenters which is proportional to the number of neutrons in the test—“fission pulse”
- Time of event is determined to ~ 1 nsec enabling precise neutron spectrum measurements
- Need to eliminate other particles are which detected (alpha particles)



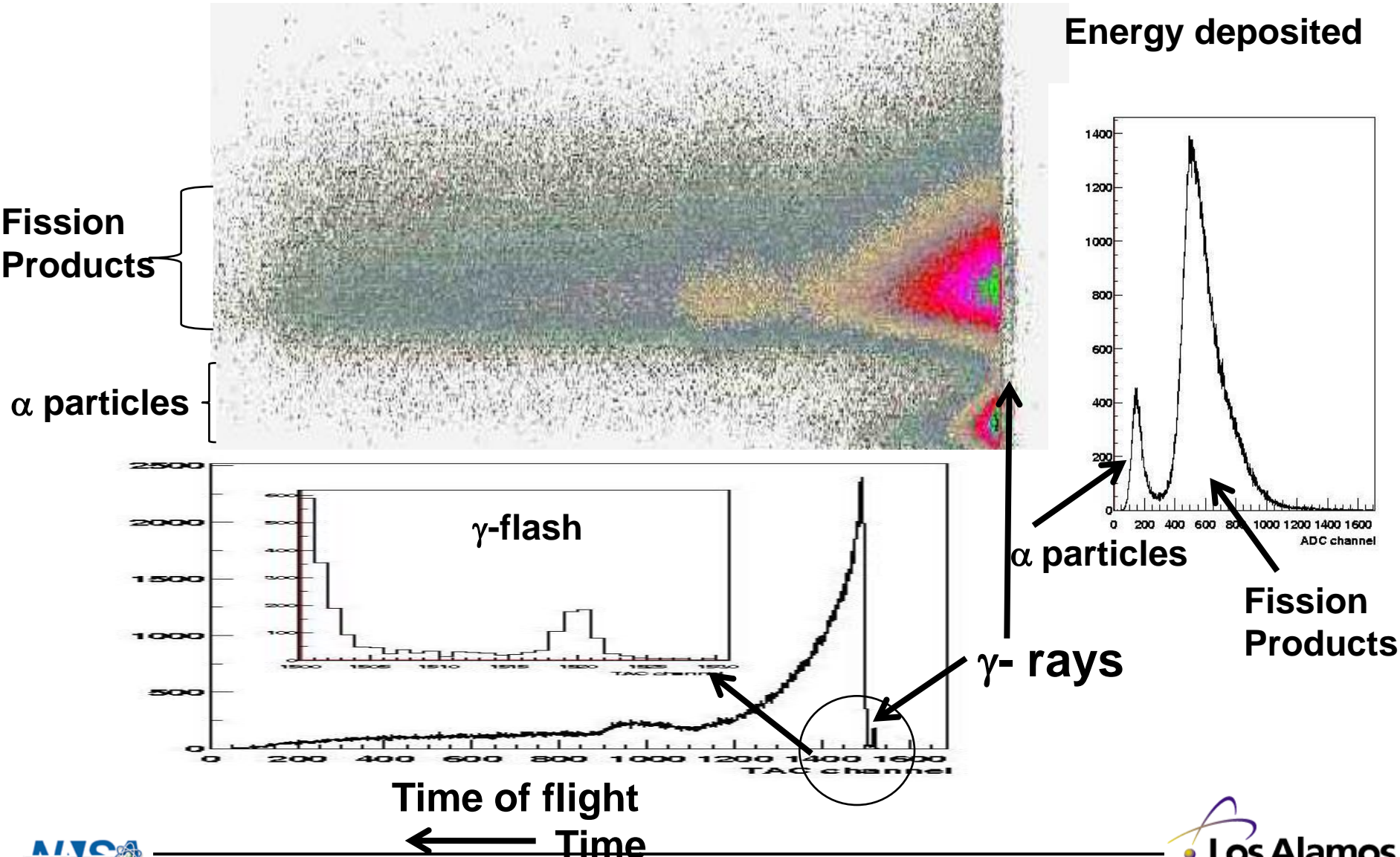
of neutrons / sec / MeV =

$$\frac{\text{[Number of fission events /sec]}}{\text{[fission cross section]} \times \text{[thickness of fission foil]}}$$

Recorded in the measurement Known from other measurements

Output from fission chamber measurement is the numbers of neutrons that pass through fission foil. This gives the number of neutrons/cm² per “fission pulse”.

Measuring fission in 2-D removes α -particle background



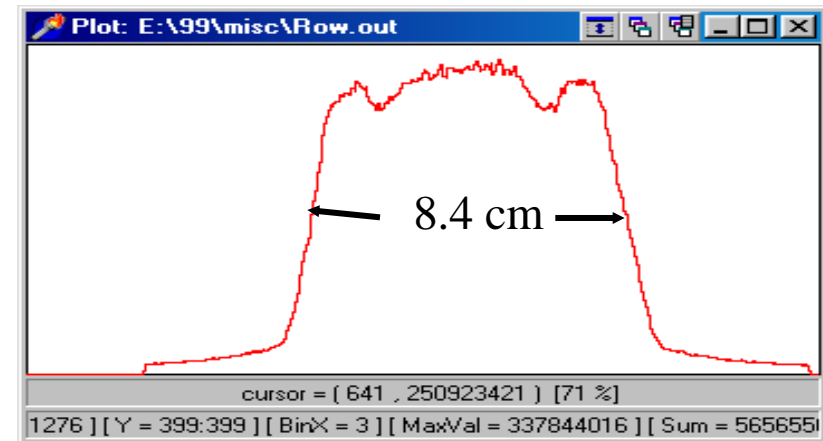
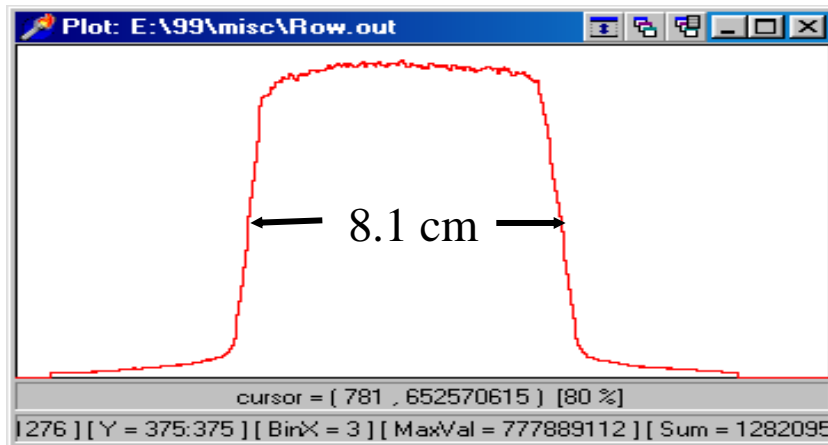
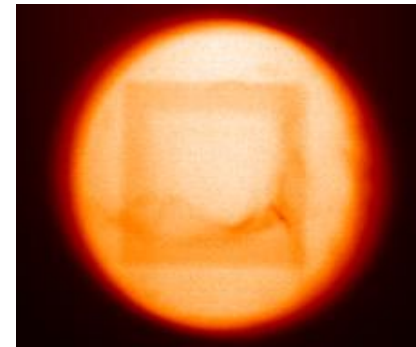
An image plate of the beam spot shows uniform exposure

- Neutron beam spot size is determined by steel collimation (~ 3 feet long)

Upstream

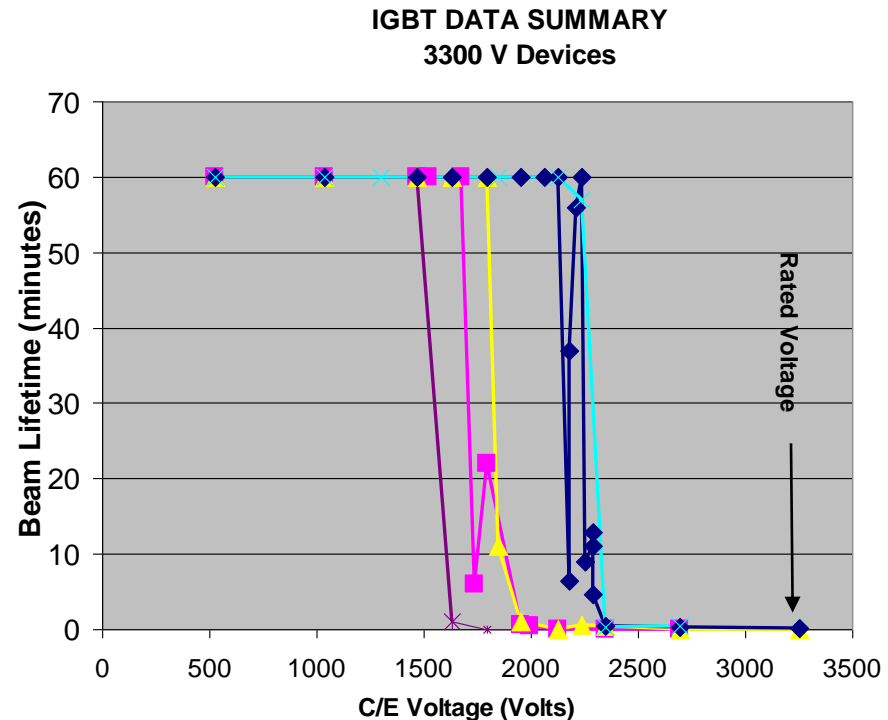


Downstream



Neutrons can cause failures in high-power semiconductor devices

- IGBT are semiconductor devices that are used in many high-power applications such as BART, hybrid cars, accelerator RF systems, etc.
- The lifetime of these devices in neutron fields depends on the electric field or the applied voltages
- Tests show a dramatic decrease in lifetime at a critical voltage which is significantly below the rated operating voltage



One neutron can stop a train

Results of LANSCE/WNR measurements determine problem with ASCI Q-Machine

- The ASCI Q-Machine has 2048 nodes with a total of 8192 processors.
- During commissioning, it was observed that the Q-machine had a larger than expected failure rate. Approximately 20 fails / week (~3 fails / day).
- The question was whether this could be the result of neutron single-event upset.



ASCI Q-Machine at Los Alamos National Laboratory

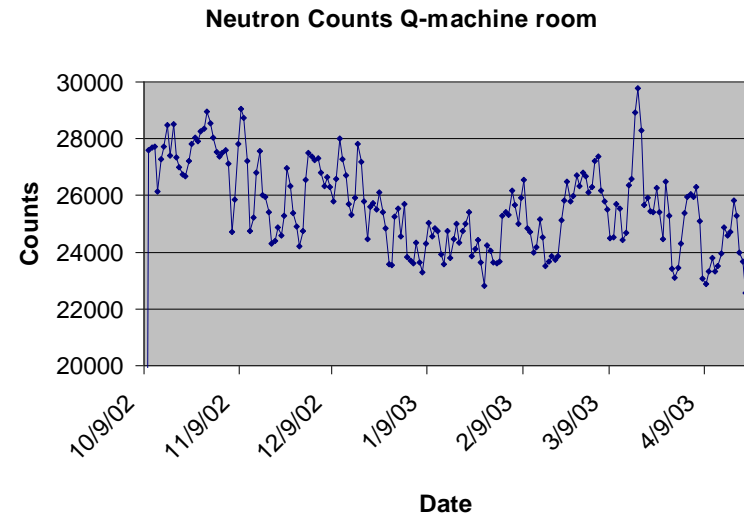
$$\# \text{ Fails/day} \sim [\# \text{ of fails/neutron}] * [\# \text{ neutrons/day}]$$

Measured at LANSCE

Cosmic-ray neutron flux

The neutron environment and the system response was measured

- The neutron intensity was measured in the Q-Machine room. The values obtained agreed with the Goldhagen values
- The system response was measured by putting one module of the Q-Machine in the LANSCE/WNR beam.
- Results of measurement accounted for approximately 80% of the failures. (IEEE Trans. Dev. Mat. Reliab. 5 2005)
- The failures were traced to a cache memory that was not error corrected.
- This result may have significant impact on future large computer systems



One neutron can stop a calculation

Santa Fe New Mexican February 2004

“..Q’s weakness is the result of...cosmic ray bombardment...a microprocessor that doesn’t have a backup system ..”

Issues for semiconductor testing

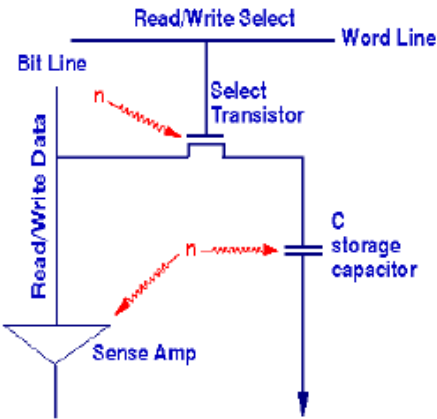
- Development of standards and specifications so customers can know what the failure rate is in the chips they purchase. Joint Electron Device Engineering Council (JEDEC) Standard JESD89.
- Knowledge of neutron flux in the environment of semiconductor devices is necessary. This includes the effects of packaging, geometry, orientation of devices, proximity of other objects, etc. MC modeling
- Precise measurement of neutron fluxes in testing laboratories so different tests can be compared
- Good, validated models, including nuclear data, that predict failures are need to be developed and improved.
- Measurement of neutron energy dependent failure rate for various devices $f_n(E_n)$
of fails / neutron as function of neutron energy
 - “Monoenergetic” neutron sources
 - Spectrum unfolding
 - Time of flight
- Calibration of accelerated testing predictions with environmental testing.

Summary

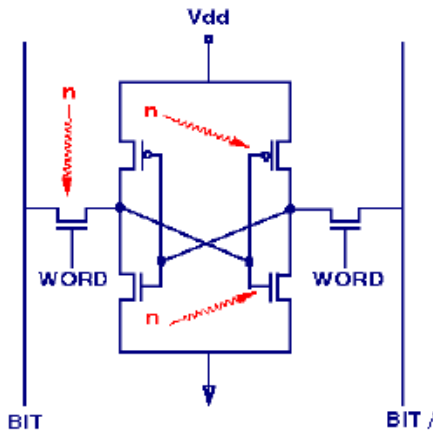
- **Single Event Effects are a very significant failure mode in modern semiconductor devices that may limit their reliability**
- **Accelerated testing is important for semiconductor industry**
- **Considerable more work is needed in this field to mitigate the problem**
- **Mitigation of this problem will probably come from Nuclear Scientists and Electrical Engineers working together**

End of talk

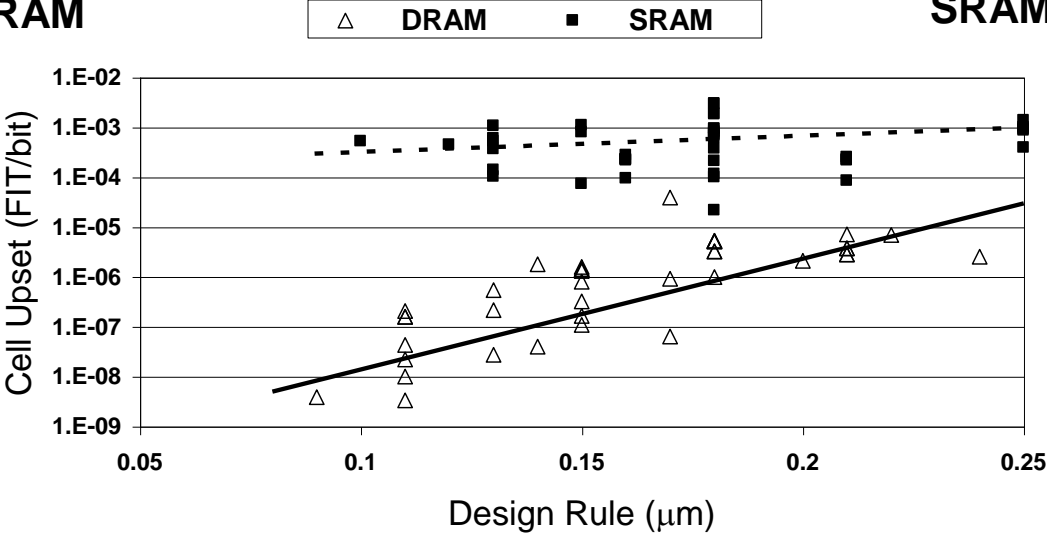
SRAM and DRAM upset rates depend on feature size



DRAM

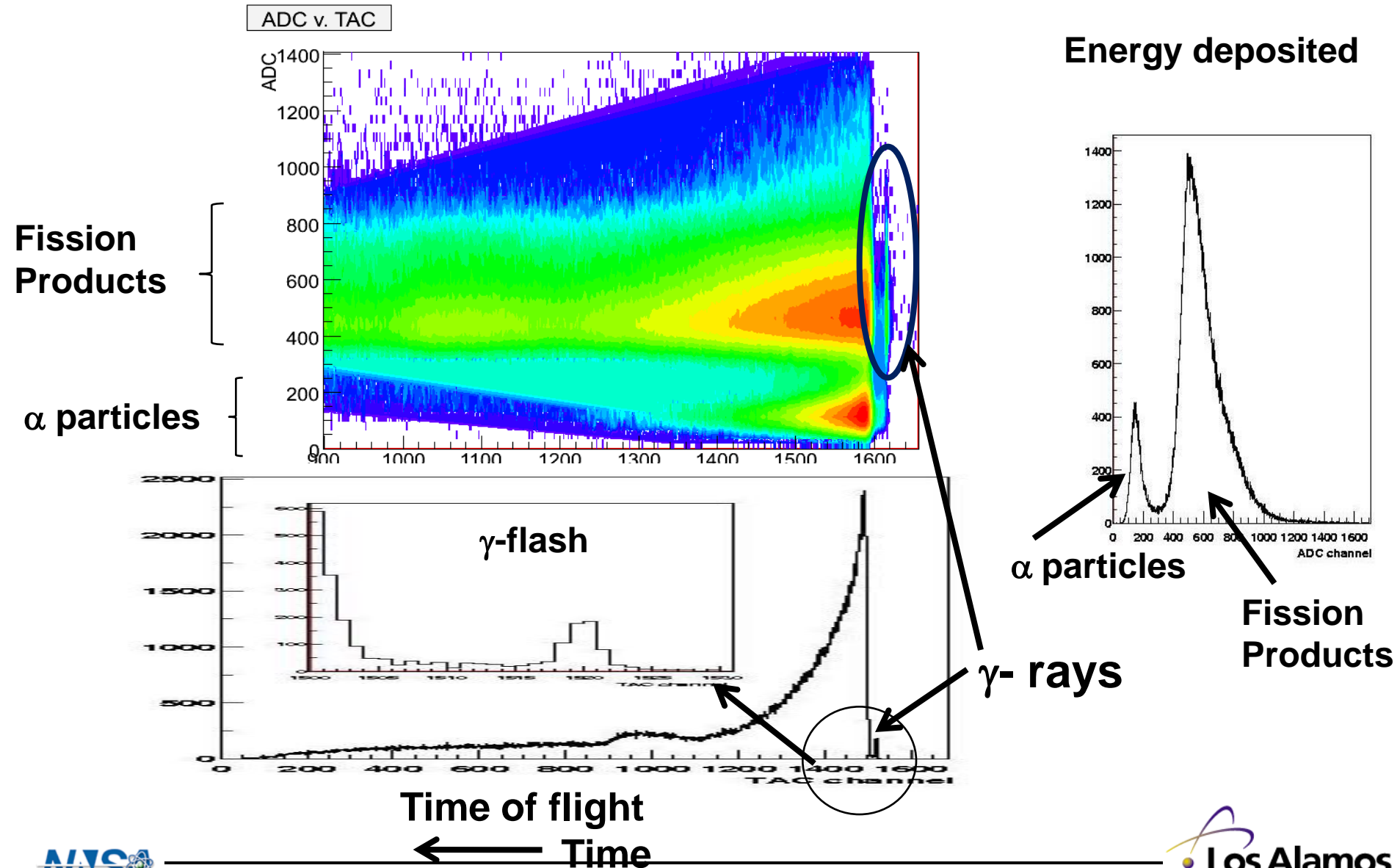


SRAM



A FIT or Failure-in-Time is the number of failures in 10^9 hours of operation
At 1 FIT a 1GB memory will fail once an hour

Measuring fission in 2-D removes α -particle background



Issues for industry users

- **Easy access to facility**
 - Simple agreements
 - Scheduling
 - Approval process for users
 - Inexpensive to use
 - Easy to travel to facility
 - Internet available
- **Easy set up of experiments**
 - Simple delivery of user equipment
 - Simple shipping to and from facility
 - Easy release of activated equipment
 - Ability to handle activated samples
- **Experiment operation**
 - Reliable accelerator operation
 - Accurate measurement of neutron flux
 - Neutron flux information can be part of their data stream
 - Easy to change beam spot size
 - Easy to connect and set up their equipment
- **Other**
 - Good restaurants and accommodations

The cosmic-ray neutron flux depends on altitude

- Neutron flux at different altitudes can be obtained by

$$I(A_1)/I(A_2) = \exp[(A_2 - A_1)/L]$$

- L is attenuation length of particle
- $L \sim 136 \text{ cm}^2/\text{g}$ for neutrons
- L is different for other particles
- A is the thickness of the air in g/cm^2
- $A(H) = 1033 - (0.03648H) + 4.2610^{-7}H^2$
grams/ cm^2
 - H is the altitude above sea level in ft
(Zeigler, IBM Journal of Research and Dev. 42, 1998)
- Thickness of air at sea level is $1033 \text{ g}/\text{cm}^2$
which is equivalent to over 4 feet of steel
or 10 feet of concrete !!!

